

EAST SEARCH

1/11/06

L#	Hits	Search String	Databases
S1	566094	(integrated or digital) near2 circuit\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S2	40	S1 and ((bus near2 (performance or traffic)) with (simulat\$3 or evaluat\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S3	1665	S1 and (bus with (simulat\$3 or evaluat\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S4	2232	S1 and (bus near2 (performance or traffic))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S5	210	S3 and S4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S6	210	S2 or S5	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S7	23	S6 and (high near2 level near2 language\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S8	173	S6 and (source\$1 or algorithm)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S9	88	S6 and (source\$1 and algorithm)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S10	27	S6 and (bus with hardware with software)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S11	156	S6 and (bus with data with transfer\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S12	8	S6 and (evaluation with function\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S13	11	S6 and (modifi\$3 with source\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S14	1	S6 and ("general purpose" near2 language\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S15	60	S6 and (architecture with design)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S16	55	S11 and S15	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S17	24	S6 and (bus with process\$3 with rate\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S18	2	S6 and (bus with traffic\$3 with rate\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S19	132	S6 and (bus with traffic\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S20	11	S6 and (high near2 level near2 design\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S21	1	S6 and (performance with (feed\$3 near2 back))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S22	1	S6 and ((evaluation or verification) with (feed\$3 near2 back))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S23	24	S6 and (feed\$3 near2 back)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S24	1	S6 and (syntax with (correction or analysis))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S25	103	S7 or S9 or S10	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S26	72	S12 or S13 or S16	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S27	7	S17 and S19	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S28	51	S17 or S20 or S23 or S27	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S30	3687	S3 or S4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S31	10	S30 and (syntax with (correction or analysis))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S29	138	S25 or S26 or S28	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S32	566094	(integrated or digital) near2 circuit\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S33	40	S32 and ((bus near2 (performance or traffic)) with (simulat\$3 or evaluat\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S34	1665	S32 and (bus with (simulat\$3 or evaluat\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S35	2232	S32 and (bus near2 (performance or traffic))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S36	210	S34 and S35	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S37	210	S33 or S36	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S38	8	S37 and (evaluation with function\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S39	10	S37 and (bus with "data transfer" with evaluation)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S40	11	S37 and (high near2 level near2 design\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S41	11	S37 and (modifi\$3 with source\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S42	24	S37 and (bus with process\$3 with rate\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S43	5	S37 and (bus with processing with rate\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S44	3687	S34 or S35	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S45	7	S44 and (bus with "processing rate")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S47	3	S44 and ("high level" near2 design\$1) with performance)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S46	55	S44 and ("high level" near2 design\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB

S48	24	S37 and (feed\$3 near2 back)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S49	70	S44 and ((bus near2 performance) with (feedback\$3 or (feed near2 back)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S50	943	S32 and (bus with simulat\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S51	703	S50 and (source\$1 or (programming near2 language\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S52	168	S51 and (bus with (performance or evaluat\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S53	83	S52 and (hardware with software)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S54	403	S50 and (language\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S55	62	S53 and S54	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S56	1	S50 and ("bus traffic" with (count\$3 or increment\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S57	1	S50 and (bus with traffic with (count\$3 or increment\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S58	1	S50 and (bus with evaluation with increment\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S59	45	(integrated or digital) near2 circuit\$1 with ("architecture design")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S60	4890	((integrated or digital) near2 circuit\$1) with simulat\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S62	5	((integrated or digital) near2 circuit\$1) with co-simulat\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S63	17	((integrated or digital) near2 circuit\$1) same co-simulat\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S64	4939	S59 or S60 or S63	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S65	56	S64 and (bus near2 (traffic or performance or "data transfer"))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S66	161	S64 and ((partition\$3 or allocat\$3) with (hardware or software))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S67	13	S64 and (bus near2 ((process\$3 near2 rate) or rate))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S68	40	S64 and ((algorithm or application) with "source code")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S69	0	S64 and (profil\$3 with "source code")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S70	0	S64 and (profil\$3 with "data transfer")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S71	117	S64 and (profil\$3 with (simulat\$3 or bus))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S72	4	S66 and S71	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S73	333	S65 or S66 or S67 or S68 or S71 or S72	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S74	753	((integrated or digital) near2 circuit\$1) and ("architecture design")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S75	5612	S64 or S74	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S78	84	S75 and (bus near2 (traffic or performance or "data transfer"))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S79	228	S75 and ((partition\$3 or allocat\$3) with (hardware or software))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S80	31	S75 and (bus near2 ((process\$3 near2 rate) or rate))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S81	71	S75 and ((algorithm or application) with "source code")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S82	0	S75 and (profil\$3 with "source code")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S83	1	S75 and (profil\$3 with "data transfer")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S84	125	S75 and (profil\$3 with (simulat\$3 or bus))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S85	7	S79 and S84	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S86	446	S78 or S79 or S80 or S81 or S83 or S84 or S85	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S87	17	S75 and (profil\$3 with software)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S88	45	((integrated or digital) near2 circuit\$1) with ("architecture design")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S89	4890	((integrated or digital) near2 circuit\$1) with simulat\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S90	17	((integrated or digital) near2 circuit\$1) same co-simulat\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S91	4939	S88 or S89 or S90	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S92	753	((integrated or digital) near2 circuit\$1) and ("architecture design")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S93	5612	S91 or S92	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S94	84	S93 and (bus near2 (traffic or performance or "data transfer"))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S95	228	S93 and ((partition\$3 or allocat\$3) with (hardware or software))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S96	31	S93 and (bus near2 ((process\$3 near2 rate) or rate))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S97	71	S93 and ((algorithm or application) with "source code")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S98	1	S93 and (profil\$3 with "data transfer")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S99	125	S93 and (profil\$3 with (simulat\$3 or bus))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S100	7	S95 and S99	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S101	446	S94 or S95 or S96 or S97 or S98 or S99 or S100	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S102	131	S93 and (bus near2 (traffic or performance or "data transfer"))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB

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Results of search set L29:S25 or S26 or S28

Document Kind	Codes Title	Issue Date	Current OR	Abstract
US 20050128489 A1	Parametric optimization of optical metrology model	20050616	356/601	
US 20050122500 A1	System and method for lithography simulation	20050609	355/67	
US 20050120327 A1	System and method for lithography simulation	20050602	716/20	
US 20050120012 A1	Adaptive hierarchy usage monitoring HVAC control system	20050602	707/3	
US 20050108667 A1	METHOD FOR DESIGNING AN INTEGRATED CIRCUIT HAVING MULTIPLE VOLTAGE DOF	20050519	716/4	
US 20050102125 A1	Inter-chip communication system	20050512	703/14	
US 20050097500 A1	System and method for lithography simulation	20050505	716/20	
US 20050094729 A1	Software and hardware partitioning for multi-standard video compression and decompression	20050505	375/240.16	
US 20050091633 A1	System and method for lithography simulation	20050428	716/20	
US 20050086565 A1	System and method for generating a test case	20050421	714/741	
US 20050081170 A1	Method and apparatus for accelerating the verification of application specific integrated circuit	20050414	716/6	
US 20050081130 A1	Using constrained scan cells to test integrated circuits	20050414	714/726	
US 20050076322 A1	System and method for lithography simulation	20050407	716/20	
US 20050076282 A1	System and method for testing a circuit design	20050407	714/739	
US 20050071706 A1	Slew rate control mechanism	20050331	713/503	
US 20050065762 A1	ESD protection device modeling method and ESD simulation method	20050324	703/14	
US 20050057748 A1	Selecting a hypothetical profile to use in optical metrology	20050317	356/237.5	
US 20050042527 A1	Phase shift mask including sub-resolution assist features for isolated spaces	20050224	430/5	
US 20050039156 A1	Design method for essentially digital systems and components thereof and essentially digital s	20050217	716/18	
US 20050025054 A1	Extensible traffic generator for synthesis of network data traffic	20050203	370/235	
US 20050015778 A1	Method and system for expressing the algorithms for the manipulation of hardware state using	20050120	719/321	
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US 20040243959 A1	Design method for semiconductor integrated circuit device	20041202	716/7	
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US 20040214150 A1	Interaction education system for teaching patient care	20041028	434/273	
US 20040209169 A1	Method of Verifying the Placement of Sub-Resolution Assist Features in a Photomask Layout	20041021	430/5	
US 20040204928 A1	Simulator apparatus and related technology	20041014	703/13	
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US 20040153301 A1	Input pipeline registers for a node in an adaptive computing engine	20040826	712/220	
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US 20040145033 A1	Integrated circuit devices and methods and apparatuses for designing integrated circuit device	20040729	703/22	
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US 20040131267 A1	Method and apparatus for performing quality video compression and motion estimation	20040708	382/236	
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US 20040123256 A1	Software traffic generator/analyser	20040624	716/4	
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US 20040098687 A1	System and method for implementing a flexible top level scan architecture using a partitioning	20040520	716/7	
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US 20020194572 A1	Methods and apparatuses for designing integrated circuits	20021219 716/1
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US 20020095304 A1	System, method, and apparatus for storing emissions and susceptibility information	20020718 705/1
US 20020087940 A1	Method for designing large standard-cell based integrated circuits	20020704 716/2
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US 20020066082 A1	Bus performance evaluation method for algorithm description	20020530 717/135
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US 20020019989 A1	Hardware and software co-simulation including simulating the cache of a target processor	20020214 716/5
US 20020016704 A1	Adjoint sensitivity determination for nonlinear circuit models	20020207 703/14
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US 20020011949 A1	Golf course yardage and information system with zone detection	20020131 342/357.06
US 20020010544 A1	Display monitor for golf cart yardage and information system	20020124 701/213
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US 20010037421 A1	Enhanced highly pipelined bus architecture	20011101 710/305
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US 6846120 B2	System for printing information on a mailing medium	20050125 400/611
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US 6640238 B1	Activity component in a presentation services patterns environment	20031028 709/201
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